Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination LOOK, KEVIN T. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2004/0124458	07-2004	Kothandaraman, Chandrasekharan	257/300
	В	US-2005/0067670	03-2005	Hui, Frank Yauchee	257/529
	С	US-6,522,582	02-2003	Rao et al.	365/185.08
	D	US-4,219,836	08-1980	McElroy, David J.	257/390
	Е	US-6,911,360	06-2005	Li et al.	438/238
	F	US-4,647,340	03-1987	Szluk et al.	438/281
	G	US-6,703,680	03-2004	Toyoshima, Yoshiaki	257/529
	Н	US-2003/0122200	07-2003	Kamiya et al.	257/379
	ı	US-6,525,397	02-2003	Kalnitsky et al.	257/529
	J	US-6,258,700	07-2001	Bohr et al.	438/467
	К	US-4,872,140	10-1989	Graham et al.	365/96
	L	US-4,238,839	12-1980	Redfern et al.	365/96
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0			311. 1. 2		
	Р			_		
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*	•	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	J	
	٧	
	W	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.